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WELLS ST. JOHN, P.S.

JUL 13 2004

5098383424 P.01/03

OFFICIAL**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

Patent Application Serial No. 10/624,627
Filing Date July 21, 2003
Inventor Luan C. Tran
Assignee Micron Technology, Inc.
Group Art Unit 2811
Examiner..... Jennifer J. Kennedy
Attorney Docket No. MI22-2358
Title: Methods of Forming Semiconductor Constructions

Mail Stop Amendment
Commissioner for Patents
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Alexandria, VA 22313-1450

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1. Certificate of Facsimile Transmission
2. Supplemental Information Disclosure Statement
3. PTO-1449

Dated: July 13, 2004

By:

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NUMBER OF PAGES IN FACSIMILE: 3

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Although it is believed that no fees are due, the Commissioner is hereby authorized to charge any fees under 37 C.F.R. 1.16 and 1.17 which may be required by this paper to Deposit Account No. 23-0925.

Dated: July 13, 2004

By:

Jennifer J. Taylor

Jennifer J. Taylor, Ph.D.
Reg. No. 48,711

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priority Examiner Kennedy, Jennifer J.
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SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

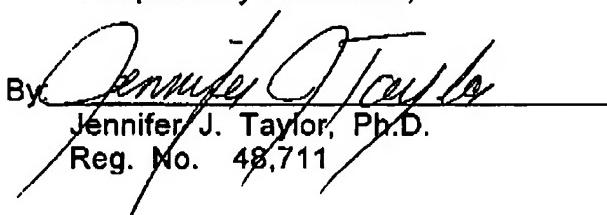
References –See Attached Form PTO-1449

The attached form PTO-1449 is submitted in compliance with 37 CFR § 1.56. Copies of the cited art are included with the exception of U.S. patents and published U.S. applications (1276 OG 55). No admission is made regarding whether all the submitted references are prior art.

This Supplemental Information Disclosure Statement is being filed within three months of the filing date of the application or before the mailing date of a first Office Action, whichever occurs last. Therefore, no fee is believed to be required. However, in the event that a fee is required for filing this Supplemental Information Disclosure Statement, please charge the fee specified under 37 C.F.R. § 1.17(p) to Deposit Account No. 23-0925.

Respectfully submitted,

Dated: July 13, 2004

By: 
Jennifer J. Taylor, Ph.D.
Reg. No. 48,711

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5098383424 P.03/03

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10/24.627LIST OF ART CITED BY APPLICANT
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APPLICANT

Lam C. Tran

FILING DATE
July 31, 2003CROSS-
REF

U.S. PATENT DOCUMENTS

Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date (If appropriate)
	AM	6,521,487	02-2003	Chen et al.			
	AN	6,492,694	12-2002	Noble et al.			
	AC	6,469,165 B1	10-2002	Yang et al.			
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	AH	5,923,973	07-1999	Rubandi			
	AI	5,866,934	02-1999	Kadosh et al.			
	AJ						
	AK						
	AL						

FOREIGN PATENT DOCUMENTS

		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
	AM							
	AN							
	AO							
	AV							
	AQ							

CITATION REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)

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